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Jochumsen et al.

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(54) **RACK FOR SUPPORTING A MULTI-POINT ELECTRICAL PROBE HOLDER**

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**

Nov. 27, 2012 (DK) .... DA 2012 00133

(51) **LOC (10) Cl.** **10-04**
(52) **U.S. Cl.**
USPC **D10/80**; D10/103
(58) **Field of Classification Search**
CPC G01R 1/06783; G01R 27/08; G01R 27/14; G01R 27/0408; G01R 27/0483; G01R 27/0404; G01R 31/2648; G01R 31/2891; G01R 31/2867
USPC D8/354; D10/80, 94, 103; D13/173; D14/217; 324/72.5, 149, 545, 324/713–719, 754.03, 754.04, 754.5, 324/754.11, 754.09, 754.2, 755.01, 755.07, 324/756.01, 756.02, 757.01, 73.1
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D400,865 S *	11/1998	Korhonen	D10/103
7,151,368 B2 *	12/2006	Joung et al.	324/757.01
7,253,649 B1 *	8/2007	Chen	324/754.04
7,898,275 B1 *	3/2011	Arnold et al.	324/756.01

* cited by examiner

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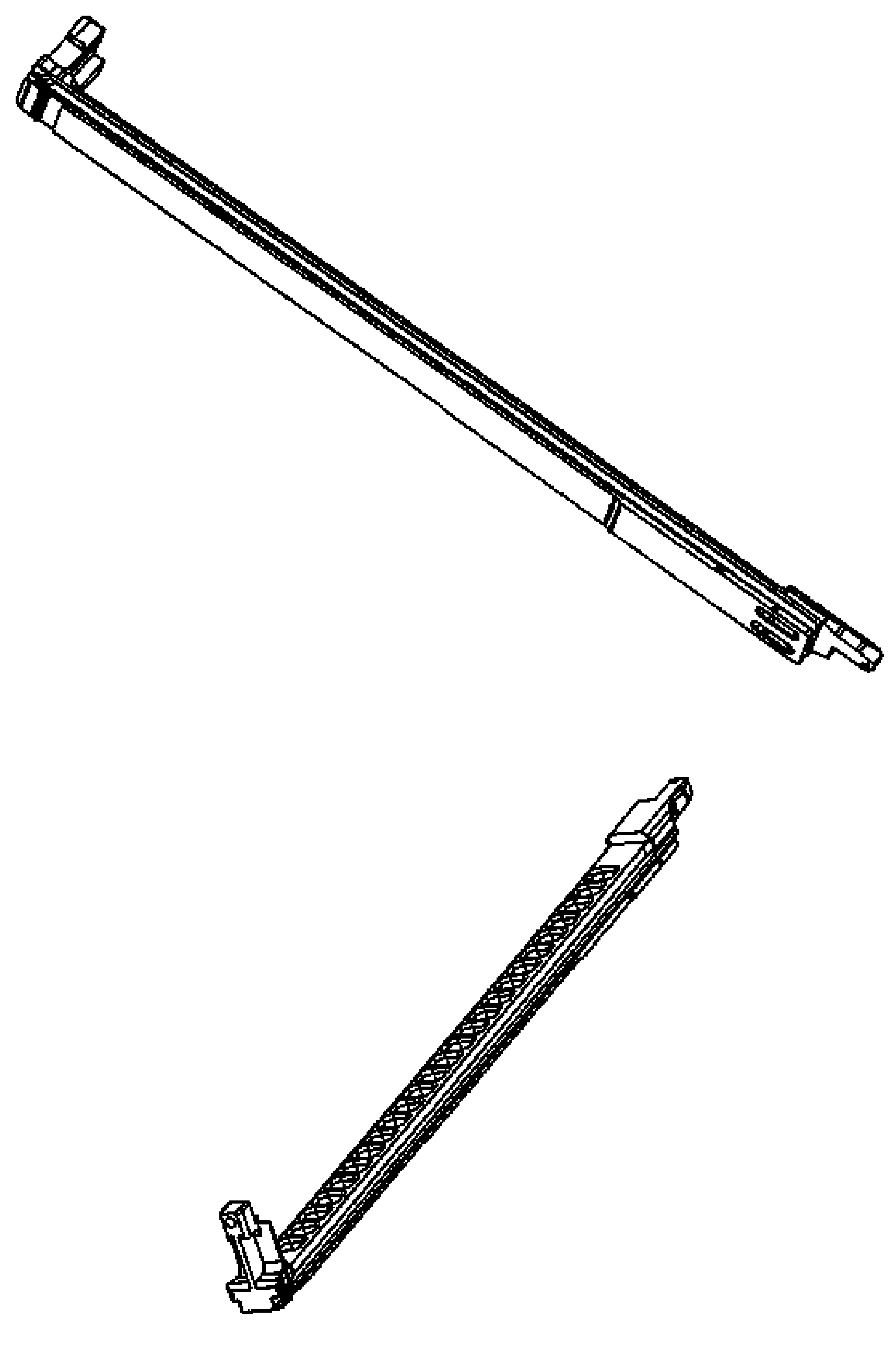
(57) **CLAIM**

The ornamental design for a rack for supporting a multi-point electrical probe holder, as shown.

DESCRIPTION

FIG. **1** is a perspective view, taken from the bottom, rear, and left side, of a rack for supporting a multi-point electrical probe holder, in accordance with our new design;
FIG. **2** is a perspective view of the rack for supporting a multi-point electrical probe holder shown in FIG. **1**, taken from the top, front, and left side;
FIG. **3** is a bottom plan view of the rack for supporting a multi-point electrical probe holder shown in FIG. **1**;
FIG. **4** is a right side elevation view of the rack for supporting a multi-point electrical probe holder shown in FIG. **1**;
FIG. **5** is a left side elevation view of the rack for supporting a multi-point electrical probe holder shown in FIG. **1**;
FIG. **6** is a top plan view of the rack for supporting a multi-point electrical probe holder shown in FIG. **1**;
FIG. **7** is a rear elevation view of the rack for supporting a multi-point electrical probe holder shown in FIG. **1**; and,
FIG. **8** is a front elevation view of the rack for supporting a multi-point electrical probe holder shown in FIG. **1**.

1 Claim, 8 Drawing Sheets



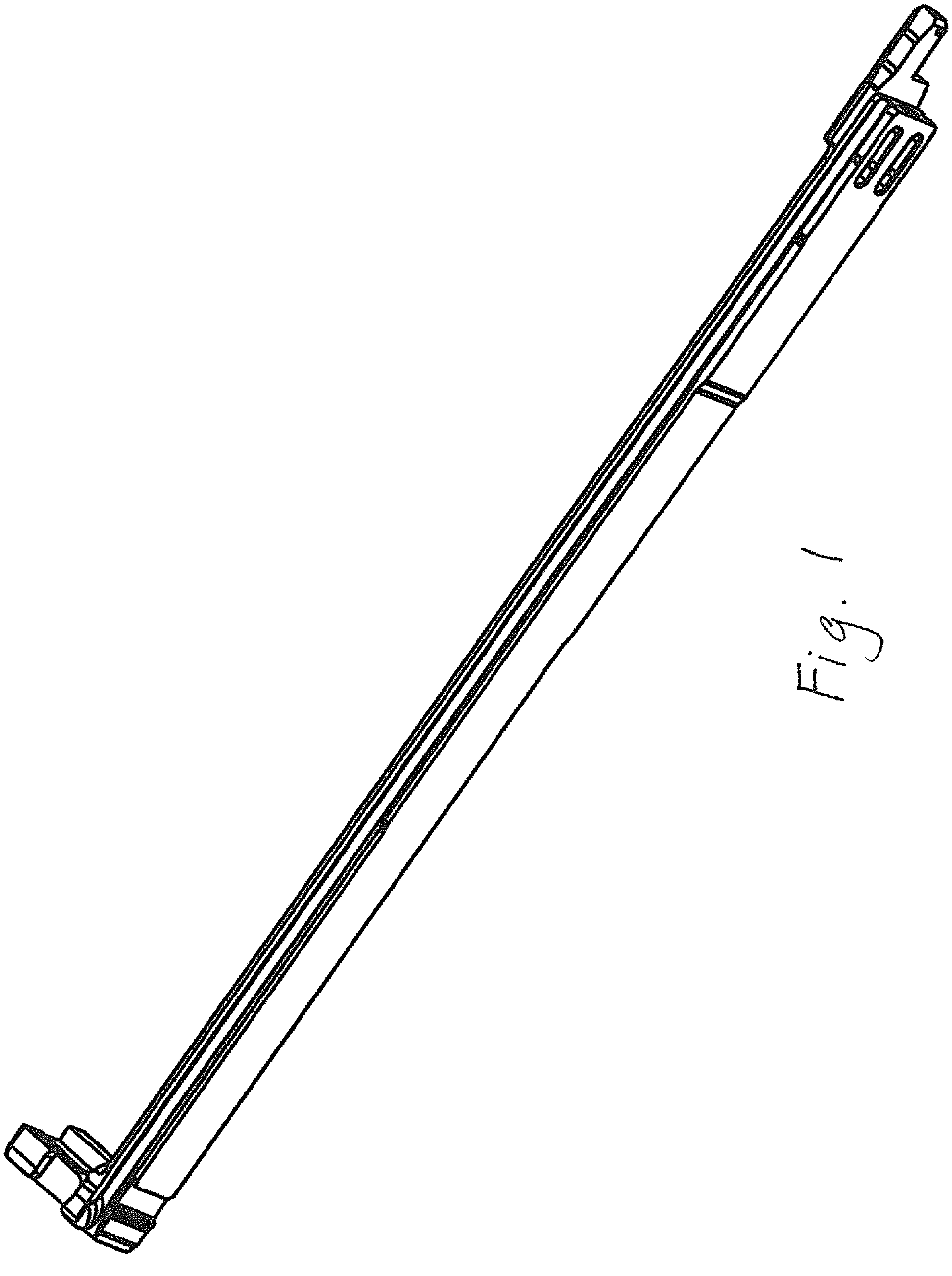


Fig. 1

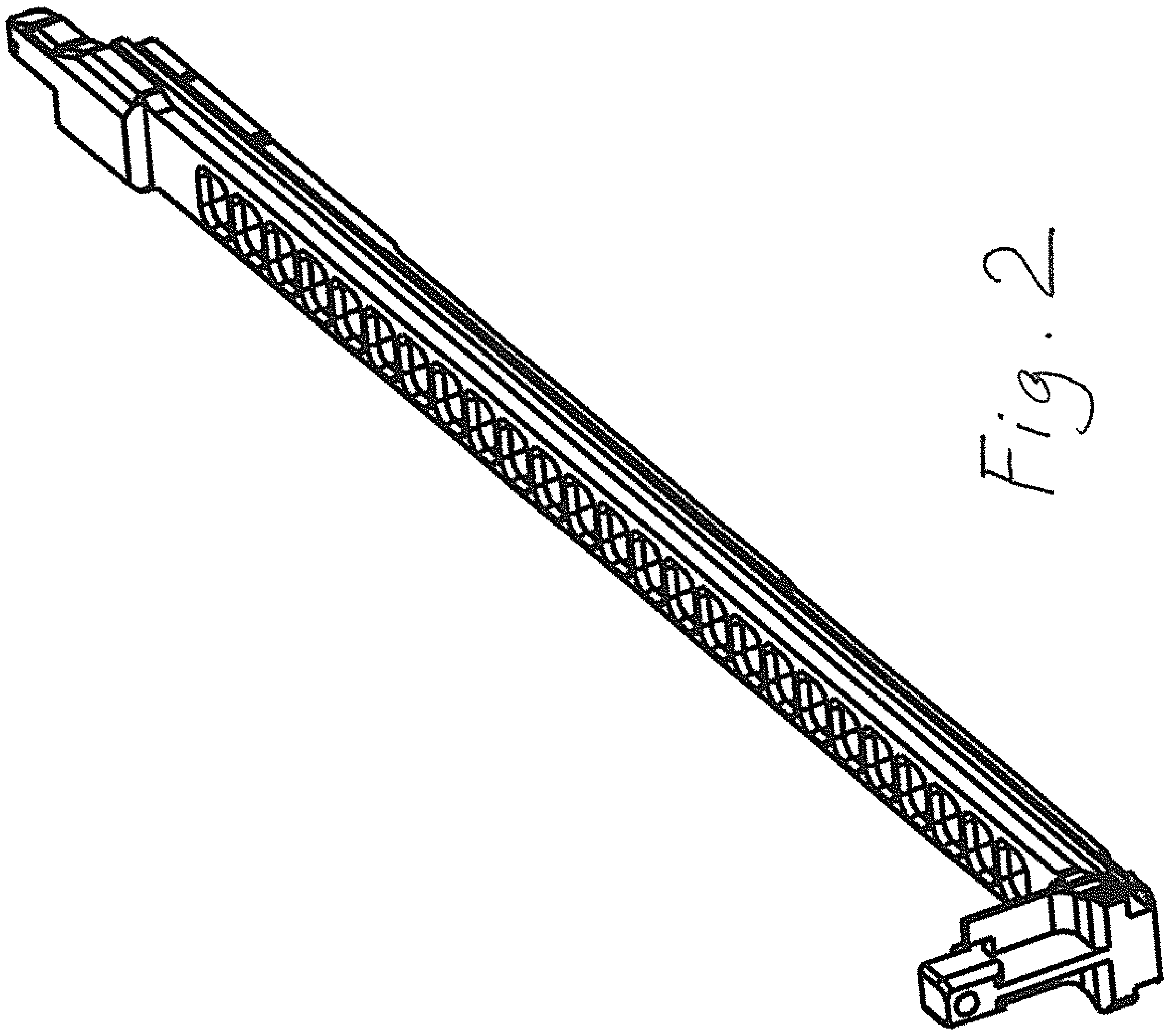


Fig. 2

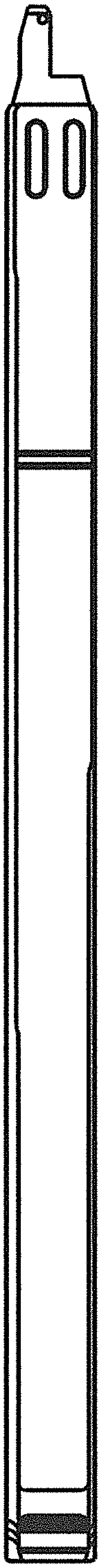


Fig. 3

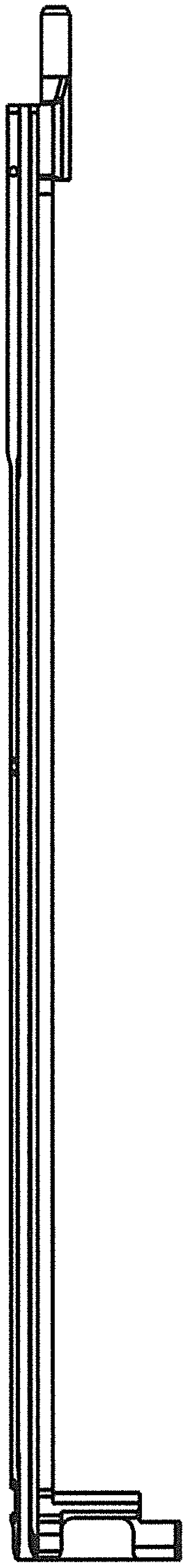


Fig. 4

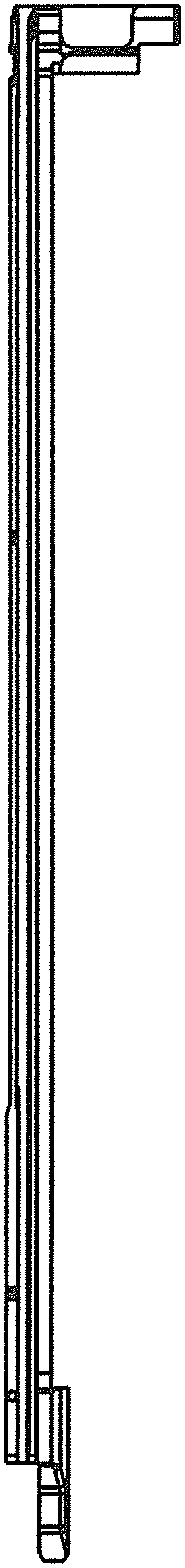


Fig. 5

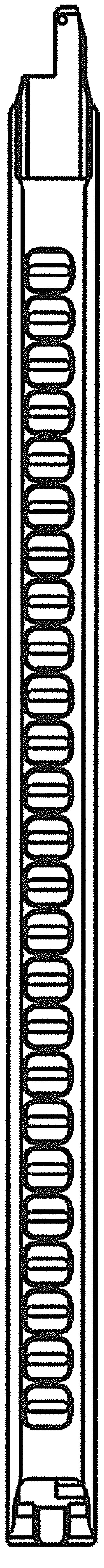


Fig. 6

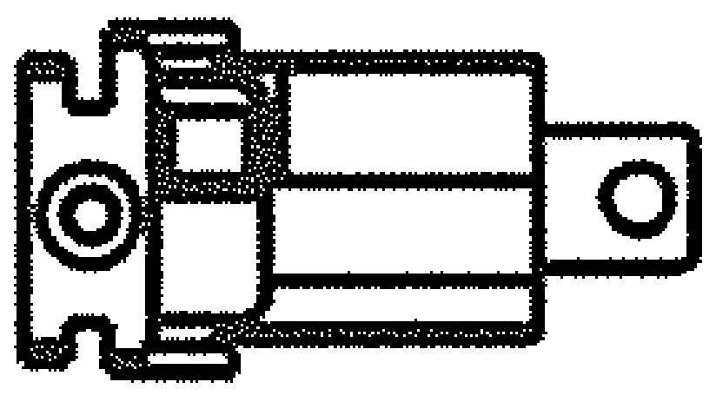


Fig. 7

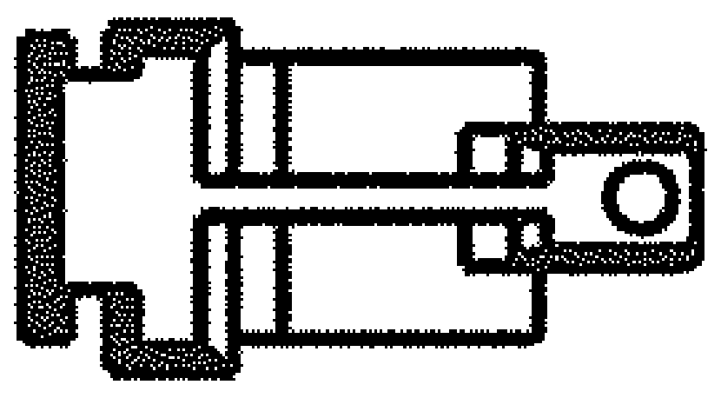


Fig. 8